

# XN04505G

## Silicon NPN epitaxial planar type

For general amplification (Tr1)

For amplification of low-frequency output (Tr2)

### ■ Features

- Two elements incorporated into one package
- Reduction of the mounting area and assembly cost by one half

### ■ Basic Part Number

- 2SD0601A + 2SD1328

### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter		Symbol	Rating	Unit
Tr1	Collector-base voltage (Emitter open)	$V_{\text{CBO}}$	60	V
	Collector-emitter voltage (Base open)	$V_{\text{CEO}}$	50	V
	Emitter-base voltage (Collector open)	$V_{\text{EBO}}$	7	V
	Collector current	$I_{\text{C}}$	100	mA
	Peak collector current	$I_{\text{CP}}$	200	mA
Tr2	Collector-base voltage (Emitter open)	$V_{\text{CBO}}$	25	V
	Collector-emitter voltage (Base open)	$V_{\text{CEO}}$	20	V
	Emitter-base voltage (Collector open)	$V_{\text{EBO}}$	12	V
	Collector current	$I_{\text{C}}$	0.5	A
	Peak collector current	$I_{\text{CP}}$	1	A
Overall	Total power dissipation	$P_{\text{T}}$	300	mW
	Junction temperature	$T_{\text{j}}$	150	$^\circ\text{C}$
	Storage temperature	$T_{\text{stg}}$	-55 to +150	$^\circ\text{C}$

### ■ Package

- Code

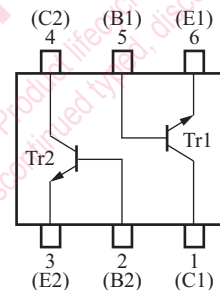
Mini6-G3

- Pin Name

- |                    |                    |
|--------------------|--------------------|
| 1: Collector (Tr1) | 4: Collector (Tr2) |
| 2: Base (Tr2)      | 5: Base (Tr1)      |
| 3: Emitter (Tr2)   | 6: Emitter (Tr1)   |

### ■ Marking Symbol: DZ

### ■ Internal Connection



## ■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

### • Tr1

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-base voltage (Emitter open)	$V_{\text{CBO}}$	$I_{\text{C}} = 10 \mu\text{A}, I_{\text{E}} = 0$	60			V
Collector-emitter voltage (Base open)	$V_{\text{CEO}}$	$I_{\text{C}} = 2 \text{ mA}, I_{\text{B}} = 0$	50			V
Emitter-base voltage (Collector open)	$V_{\text{EBO}}$	$I_{\text{E}} = 10 \mu\text{A}, I_{\text{C}} = 0$	7			V
Collector-base cutoff current (Emitter open)	$I_{\text{CBO}}$	$V_{\text{CB}} = 20 \text{ V}, I_{\text{E}} = 0$			0.1	$\mu\text{A}$
Collector-emitter cutoff current (Base open)	$I_{\text{CEO}}$	$V_{\text{CE}} = 10 \text{ V}, I_{\text{B}} = 0$			100	$\mu\text{A}$
Forward current transfer ratio	$h_{\text{FE}}$	$V_{\text{CE}} = 10 \text{ V}, I_{\text{C}} = 2 \text{ mA}$	160		460	—
Collector-emitter saturation voltage	$V_{\text{CE(sat)}}$	$I_{\text{C}} = 100 \text{ mA}, I_{\text{B}} = 10 \text{ mA}$		0.3	0.5	V
Transition frequency	$f_{\text{T}}$	$V_{\text{CB}} = 10 \text{ V}, I_{\text{E}} = -2 \text{ mA}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance (Common base, input open circuited)	$C_{\text{ob}}$	$V_{\text{CB}} = 10 \text{ V}, I_{\text{E}} = 0, f = 1 \text{ MHz}$		3.5		pF

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

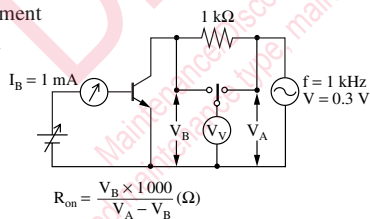
### • Tr2

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-base voltage (Emitter open)	$V_{\text{CBO}}$	$I_{\text{C}} = 10 \mu\text{A}, I_{\text{E}} = 0$	25			V
Collector-emitter voltage (Base open)	$V_{\text{CEO}}$	$I_{\text{C}} = 1 \text{ mA}, I_{\text{B}} = 0$	20			V
Emitter-base voltage (Collector open)	$V_{\text{EBO}}$	$I_{\text{E}} = 10 \mu\text{A}, I_{\text{C}} = 0$	12			V
Collector-base cutoff current (Emitter open)	$I_{\text{CBO}}$	$V_{\text{CB}} = 25 \text{ V}, I_{\text{E}} = 0$			0.1	$\mu\text{A}$
Forward current transfer ratio *1	$h_{\text{FE1}}$	$V_{\text{CE}} = 2 \text{ V}, I_{\text{C}} = 0.5 \text{ A}$	200		800	—
	$h_{\text{FE2}}$	$V_{\text{CE}} = 2 \text{ V}, I_{\text{C}} = 1 \text{ A}$	60			
Collector-emitter saturation voltage *1	$V_{\text{CE(sat)}}$	$I_{\text{C}} = 0.5 \text{ A}, I_{\text{B}} = 20 \text{ mA}$		0.13	0.40	V
Base-emitter saturation voltage *1	$V_{\text{BE(sat)}}$	$I_{\text{C}} = 0.5 \text{ A}, I_{\text{B}} = 20 \text{ mA}$			1.2	V
Transition frequency	$f_{\text{T}}$	$V_{\text{CB}} = 10 \text{ V}, I_{\text{E}} = -50 \text{ mA}, f = 200 \text{ MHz}$		200		MHz
Collector output capacitance (Common base, input open circuited)	$C_{\text{ob}}$	$V_{\text{CB}} = 10 \text{ V}, I_{\text{E}} = 0, f = 1 \text{ MHz}$		10		pF
ON resistance *2	$R_{\text{on}}$			1.0		$\Omega$

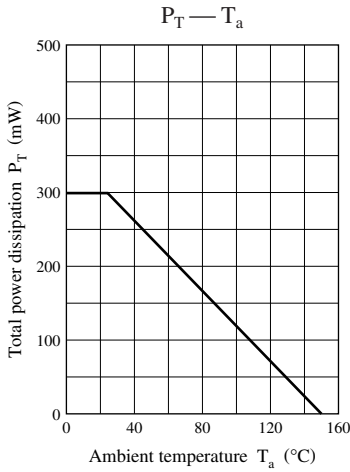
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1: Pulse measurement

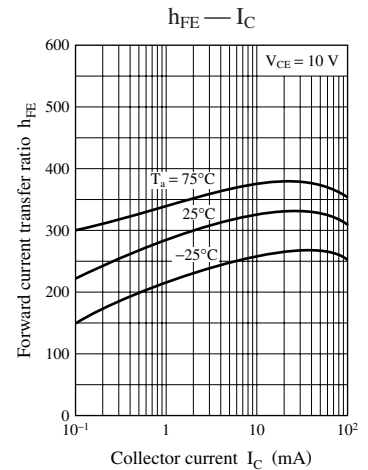
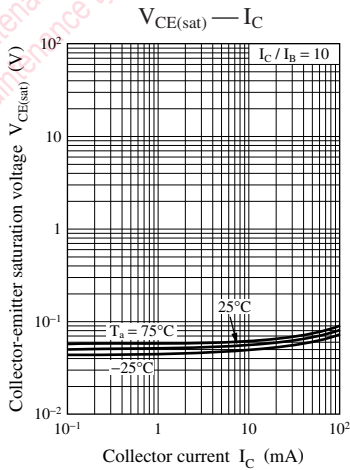
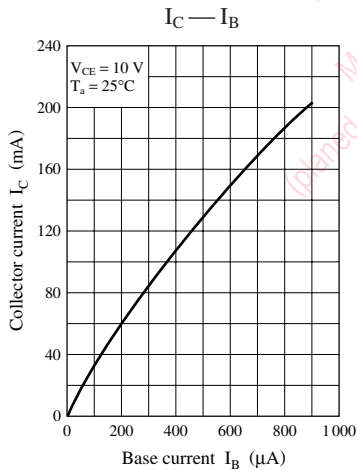
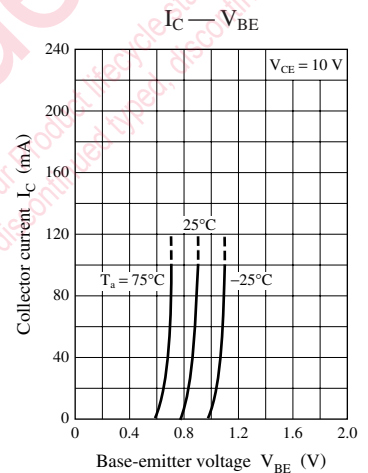
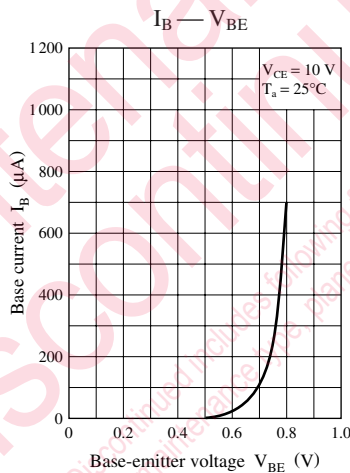
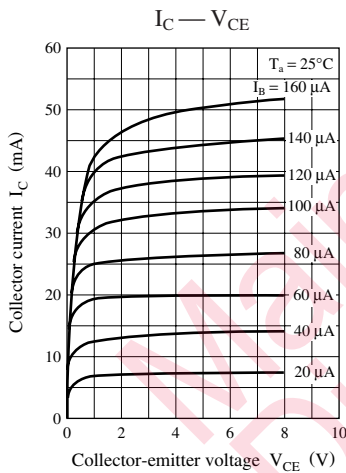
\*2:  $R_{\text{on}}$  test circuit

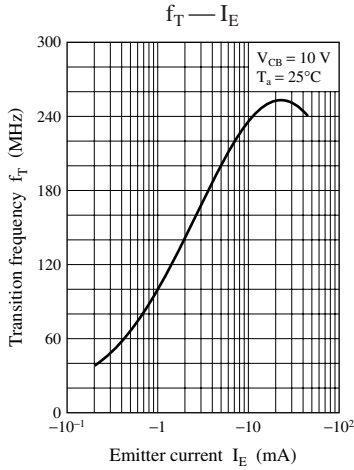


Common characteristics chart

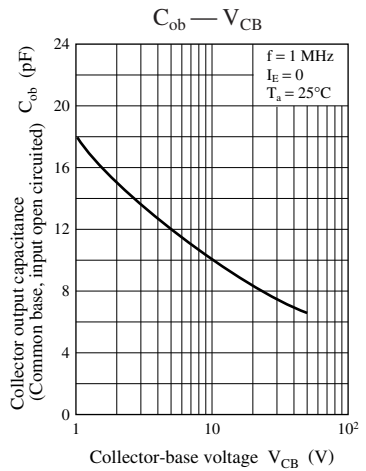
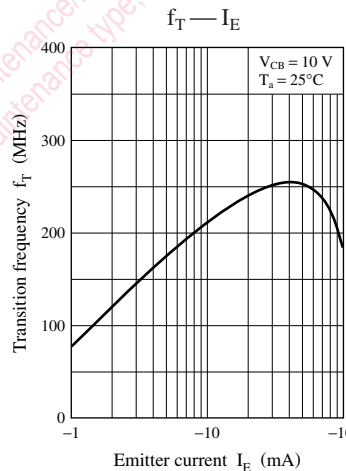
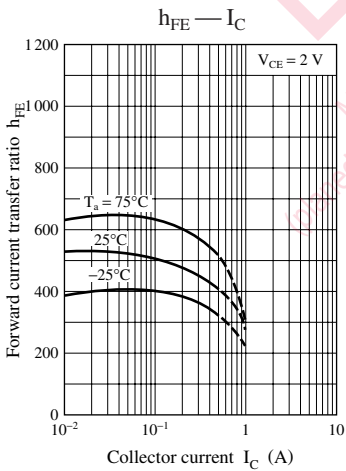
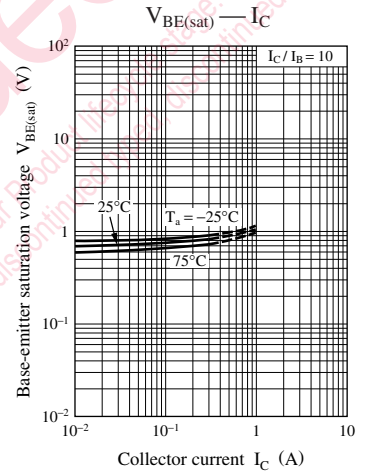
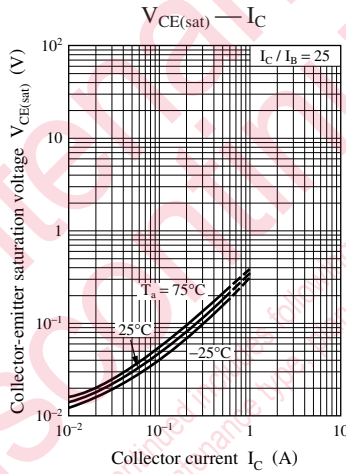
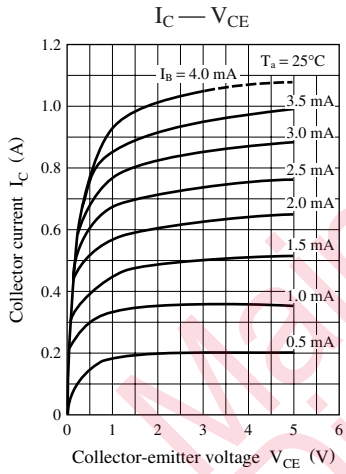


Characteristics charts of Tr1



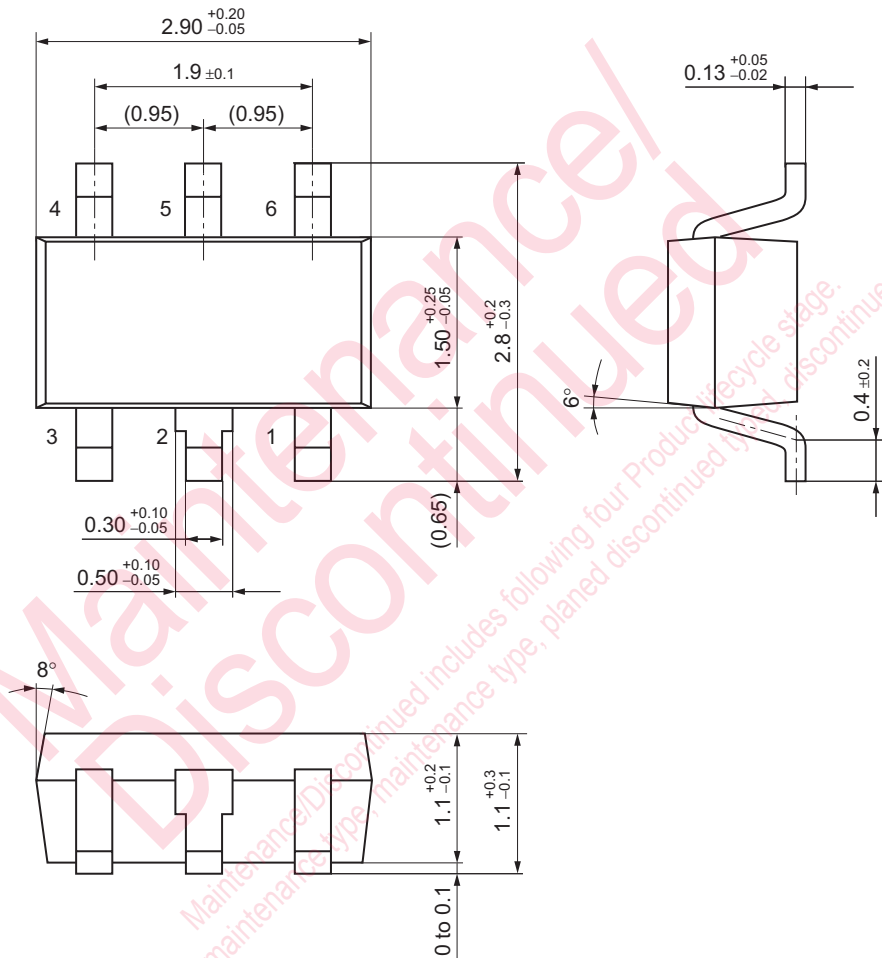


Characteristics charts of Tr2



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Unit: mm



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